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**Details**

Product Status	Obsolete
Module/Board Type	FPGA Core
Core Processor	Spartan-6 LX-100
Co-Processor	-
Speed	125MHz
Flash Size	16MB
RAM Size	1GB
Connector Type	Samtec LSHM
Size / Dimension	1.97" x 1.57" (50mm x 40mm)
Operating Temperature	0°C ~ 70°C
Purchase URL	<a href="https://www.e-xfl.com/product-detail/trenz-electronic/te0600-03bm">https://www.e-xfl.com/product-detail/trenz-electronic/te0600-03bm</a>

Table 3: eFUSE Programming Conditions<sup>(1)</sup>

Symbol	Description	Min	Typ	Max	Units
$V_{FS}$ <sup>(2)</sup>	External voltage supply	3.2	3.3	3.4	V
$I_{FS}$	$V_{FS}$ supply current	–	–	40	mA
$V_{CCAUX}$	Auxiliary supply voltage relative to GND	3.2	3.3	3.45	V
$R_{FUSE}$ <sup>(3)</sup>	External resistor from $R_{FUSE}$ pin to GND	1129	1140	1151	$\Omega$
$V_{CCINT}$	Internal supply voltage relative to GND	1.14	1.2	1.26	V
$t_j$	Temperature range	15	–	85	$^{\circ}\text{C}$

**Notes:**

1. These specifications apply during programming of the eFUSE AES key. Programming is only supported through JTAG. The AES key is only supported in the following devices: LX75, LX75T, LX100, LX100T, LX150, and LX150T.
2. When programming eFUSE,  $V_{FS}$  must be less than or equal to  $V_{CCAUX}$ . When not programming or when eFUSE is not used, Xilinx recommends connecting  $V_{FS}$  to GND. However,  $V_{FS}$  can be between GND and 3.45 V.
3. An  $R_{FUSE}$  resistor is required when programming the eFUSE AES key. When not programming or when eFUSE is not used, Xilinx recommends connecting the  $R_{FUSE}$  pin to  $V_{CCAUX}$  or GND. However,  $R_{FUSE}$  can be unconnected.

## Quiescent Current

Typical values for quiescent supply current are specified at nominal voltage, 25°C junction temperatures ( $T_j$ ). Quiescent supply current is specified by speed grade for Spartan-6 devices. Xilinx recommends analyzing static power consumption using the XPOWER™ Estimator (XPE) tool (download at <http://www.xilinx.com/power>) for conditions other than those specified in Table 5.

Table 5: Typical Quiescent Supply Current

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
$I_{CCINTQ}$	Quiescent $V_{CCINT}$ supply current	LX4	4.0	4.0	4.0	2.4	mA
		LX9	4.0	4.0	4.0	2.4	mA
		LX16	6.0	6.0	6.0	4.0	mA
		LX25	11.0	11.0	11.0	6.6	mA
		LX25T	11.0	11.0	11.0	N/A	mA
		LX45	15.0	15.0	15.0	9.0	mA
		LX45T	15.0	15.0	15.0	N/A	mA
		LX75	29.0	29.0	29.0	17.4	mA
		LX75T	29.0	29.0	29.0	N/A	mA
		LX100	36.0	36.0	36.0	21.6	mA
		LX100T	36.0	36.0	36.0	N/A	mA
		LX150	51.0	51.0	51.0	31.0	mA
		LX150T	51.0	51.0	51.0	N/A	mA
$I_{CCOQ}$	Quiescent $V_{CCO}$ supply current	LX4	1.0	1.0	1.0	1.0	mA
		LX9	1.0	1.0	1.0	1.0	mA
		LX16	2.0	2.0	2.0	2.0	mA
		LX25	2.0	2.0	2.0	2.0	mA
		LX25T	2.0	2.0	2.0	N/A	mA
		LX45	3.0	3.0	3.0	3.0	mA
		LX45T	3.0	3.0	3.0	N/A	mA
		LX75	4.0	4.0	4.0	4.0	mA
		LX75T	4.0	4.0	4.0	N/A	mA
		LX100	5.0	5.0	5.0	5.0	mA
		LX100T	5.0	5.0	5.0	N/A	mA
		LX150	7.0	7.0	7.0	7.0	mA
		LX150T	7.0	7.0	7.0	N/A	mA

## SelectIO™ Interface DC Input and Output Levels

Table 7: Recommended Operating Conditions for User I/Os Using Single-Ended Standards

I/O Standard	$V_{CCO}$ for Drivers <sup>(1)</sup>			$V_{REF}$ for Inputs		
	$V$ , Min	$V$ , Nom	$V$ , Max	$V$ , Min	$V$ , Nom	$V$ , Max
LV TTL	3.0	3.3	3.45			
LVC MOS33	3.0	3.3	3.45			
LVC MOS25	2.3	2.5	2.7			
LVC MOS18	1.65	1.8	1.95			
LVC MOS18_JEDEC	1.65	1.8	1.95			
LVC MOS15	1.4	1.5	1.6			
LVC MOS15_JEDEC	1.4	1.5	1.6			
LVC MOS12	1.1	1.2	1.3			
LVC MOS12_JEDEC	1.1	1.2	1.3			
PCI33_3 <sup>(2)</sup>	3.0	3.3	3.45			
PCI66_3 <sup>(2)</sup>	3.0	3.3	3.45			
I2C	2.7	3.0	3.45			
SMBUS	2.7	3.0	3.45			
SDIO	3.0	3.3	3.45			
MOBILE_DDR	1.7	1.8	1.9			
HSTL_I	1.4	1.5	1.6	0.68	0.75	0.9
HSTL_II	1.4	1.5	1.6	0.68	0.75	0.9
HSTL_III	1.4	1.5	1.6	–	0.9	–
HSTL_I_18	1.7	1.8	1.9	0.8	0.9	1.1
HSTL_II_18	1.7	1.8	1.9	–	0.9	–
HSTL_III_18	1.7	1.8	1.9	–	1.1	–
SSTL3_I	3.0	3.3	3.45	1.3	1.5	1.7
SSTL3_II	3.0	3.3	3.45	1.3	1.5	1.7
SSTL2_I	2.3	2.5	2.7	1.13	1.25	1.38
SSTL2_II	2.3	2.5	2.7	1.13	1.25	1.38
SSTL18_I	1.7	1.8	1.9	0.833	0.9	0.969
SSTL18_II	1.7	1.8	1.9	0.833	0.9	0.969
SSTL15_II	1.425	1.5	1.575	0.69	0.75	0.81

**Notes:**

- $V_{CCO}$  range required when using I/O standard for an output. Also required for MOBILE\_DDR, PCI33\_3, LVC MOS18\_JEDEC, LVC MOS15\_JEDEC, and LVC MOS12\_JEDEC inputs, and for LVC MOS25 inputs when  $V_{CCAUX} = 3.3V$ .
- For PCI systems, the transmitter and receiver should have common supplies for  $V_{CCO}$ .

## GTP Transceiver DC Input and Output Levels

Table 16 summarizes the DC output specifications of the GTP transceivers in Spartan-6 FPGAs. Figure 1 shows the single-ended output voltage swing. Figure 2 shows the peak-to-peak differential output voltage.

Consult [UG386: Spartan-6 FPGA GTP Transceivers User Guide](#) for further details.

Table 16: GTP Transceiver DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
DV <sub>PPIN</sub>	Differential peak-to-peak input voltage	External AC coupled	140	—	2000	mV
V <sub>IN</sub>	Absolute input voltage	DC coupled MGTAVTTRX = 1.2V	-400	—	MGTAVTTRX	mV
V <sub>CMIN</sub>	Common mode input voltage	DC coupled MGTAVTTRX = 1.2V	—	3/4 MGTAVTTRX	—	mV
DV <sub>PPOUT</sub>	Differential peak-to-peak output voltage <sup>(1)</sup>	Transmitter output swing is set to maximum setting	—	—	1000	mV
V <sub>SEOUT</sub>	Single-ended output voltage <sup>(1)</sup>	—	—	—	500	mV
V <sub>CMOUTDC</sub>	Common mode output voltage	Equation based	MGTAVTTX - V <sub>SEOUT</sub> /2			mV
R <sub>IN</sub>	Differential input resistance	—	80	100	130	Ω
R <sub>OUT</sub>	Differential output resistance	—	80	100	130	Ω
T <sub>OSKEW</sub>	Transmitter output skew	—	—	—	15	ps
C <sub>EXT</sub>	Recommended external AC coupling capacitor <sup>(2)</sup>	—	75	100	200	nF

**Notes:**

- The output swing and preemphasis levels are programmable using the attributes discussed in [UG386: Spartan-6 FPGA GTP Transceivers User Guide](#) and can result in values lower than reported in this table.
- Other values can be used as appropriate to conform to specific protocols and standards.

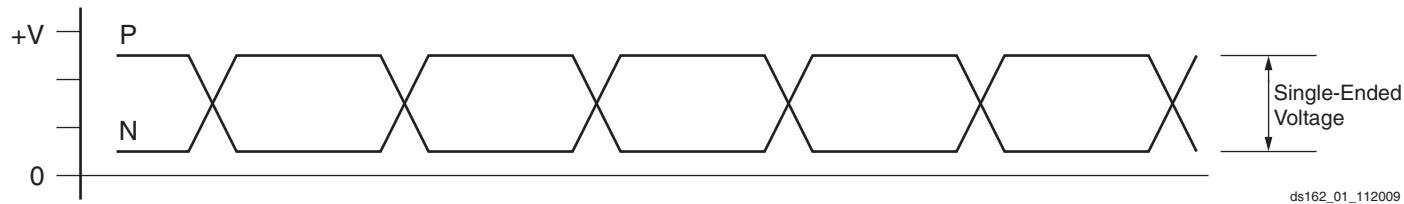


Figure 1: Single-Ended Peak-to-Peak Voltage

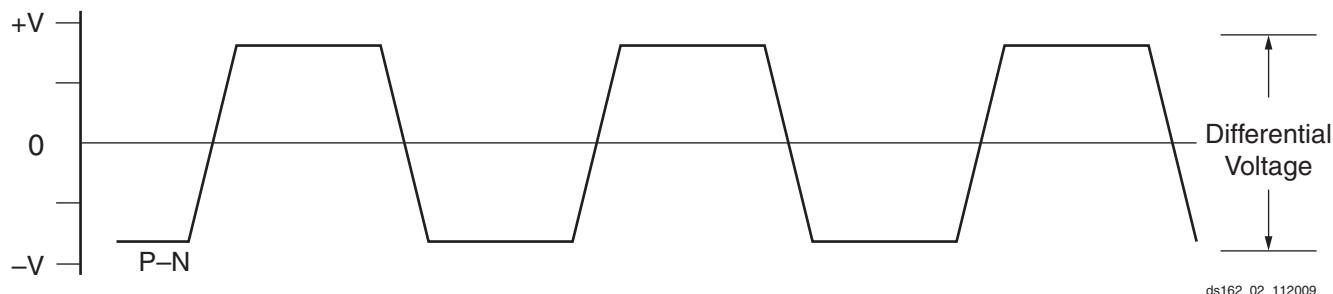


Figure 2: Differential Peak-to-Peak Voltage

Table 17 summarizes the DC specifications of the clock input of the GTP transceiver. Consult [UG386: Spartan-6 FPGA GTP Transceivers User Guide](#) for further details.

Table 28: IOB Switching Characteristics for the Commercial (XC) Spartan-6 Devices (Cont'd)

I/O Standard	T <sub>IOPI</sub>				T <sub>IOOP</sub>				T <sub>IOTP</sub>				Units	
	Speed Grade				Speed Grade				Speed Grade					
	-3	-3N	-2	-1L <sup>(1)</sup>	-3	-3N	-2	-1L <sup>(1)</sup>	-3	-3N	-2	-1L <sup>(1)</sup>		
LVCMOS33, Fast, 8 mA	1.34	1.46	1.59	1.82	2.07	2.21	2.41	3.03	2.07	2.21	2.41	3.03	ns	
LVCMOS33, Fast, 12 mA	1.34	1.46	1.59	1.82	1.65	1.79	1.99	2.62	1.65	1.79	1.99	2.62	ns	
LVCMOS33, Fast, 16 mA	1.34	1.46	1.59	1.82	1.65	1.79	1.99	2.62	1.65	1.79	1.99	2.62	ns	
LVCMOS33, Fast, 24 mA	1.34	1.46	1.59	1.82	1.65	1.79	1.99	2.62	1.65	1.79	1.99	2.62	ns	
LVCMOS25, QUIETIO, 2 mA	0.82	0.94	1.07	1.31	4.81	4.95	5.15	5.79	4.81	4.95	5.15	5.79	ns	
LVCMOS25, QUIETIO, 4 mA	0.82	0.94	1.07	1.31	3.70	3.84	4.04	4.66	3.70	3.84	4.04	4.66	ns	
LVCMOS25, QUIETIO, 6 mA	0.82	0.94	1.07	1.31	3.46	3.60	3.80	4.38	3.46	3.60	3.80	4.38	ns	
LVCMOS25, QUIETIO, 8 mA	0.82	0.94	1.07	1.31	3.20	3.34	3.54	4.12	3.20	3.34	3.54	4.12	ns	
LVCMOS25, QUIETIO, 12 mA	0.82	0.94	1.07	1.31	2.83	2.97	3.17	3.75	2.83	2.97	3.17	3.75	ns	
LVCMOS25, QUIETIO, 16 mA	0.82	0.94	1.07	1.31	2.64	2.78	2.98	3.64	2.64	2.78	2.98	3.64	ns	
LVCMOS25, QUIETIO, 24 mA	0.82	0.94	1.07	1.31	2.45	2.59	2.79	3.42	2.45	2.59	2.79	3.42	ns	
LVCMOS25, Slow, 2 mA	0.82	0.94	1.07	1.31	3.78	3.92	4.12	4.76	3.78	3.92	4.12	4.76	ns	
LVCMOS25, Slow, 4 mA	0.82	0.94	1.07	1.31	2.79	2.93	3.13	3.73	2.79	2.93	3.13	3.73	ns	
LVCMOS25, Slow, 6 mA	0.82	0.94	1.07	1.31	2.73	2.87	3.07	3.66	2.73	2.87	3.07	3.66	ns	
LVCMOS25, Slow, 8 mA	0.82	0.94	1.07	1.31	2.48	2.62	2.82	3.42	2.48	2.62	2.82	3.42	ns	
LVCMOS25, Slow, 12 mA	0.82	0.94	1.07	1.31	2.01	2.15	2.35	2.95	2.01	2.15	2.35	2.95	ns	
LVCMOS25, Slow, 16 mA	0.82	0.94	1.07	1.31	2.01	2.15	2.35	2.95	2.01	2.15	2.35	2.95	ns	
LVCMOS25, Slow, 24 mA	0.82	0.94	1.07	1.31	2.01	2.15	2.35	2.94	2.01	2.15	2.35	2.94	ns	
LVCMOS25, Fast, 2 mA	0.82	0.94	1.07	1.31	3.35	3.49	3.69	4.31	3.35	3.49	3.69	4.31	ns	
LVCMOS25, Fast, 4 mA	0.82	0.94	1.07	1.31	2.25	2.39	2.59	3.22	2.25	2.39	2.59	3.22	ns	
LVCMOS25, Fast, 6 mA	0.82	0.94	1.07	1.31	2.09	2.23	2.43	3.05	2.09	2.23	2.43	3.05	ns	
LVCMOS25, Fast, 8 mA	0.82	0.94	1.07	1.31	2.02	2.16	2.36	2.98	2.02	2.16	2.36	2.98	ns	
LVCMOS25, Fast, 12 mA	0.82	0.94	1.07	1.31	1.56	1.70	1.90	2.52	1.56	1.70	1.90	2.52	ns	
LVCMOS25, Fast, 16 mA	0.82	0.94	1.07	1.31	1.56	1.70	1.90	2.52	1.56	1.70	1.90	2.52	ns	
LVCMOS25, Fast, 24 mA	0.82	0.94	1.07	1.31	1.56	1.70	1.90	2.52	1.56	1.70	1.90	2.52	ns	
LVCMOS18, QUIETIO, 2 mA	1.18	1.30	1.43	2.04	5.92	6.06	6.26	6.80	5.92	6.06	6.26	6.80	ns	
LVCMOS18, QUIETIO, 4 mA	1.18	1.30	1.43	2.04	4.74	4.88	5.08	5.63	4.74	4.88	5.08	5.63	ns	
LVCMOS18, QUIETIO, 6 mA	1.18	1.30	1.43	2.04	4.05	4.19	4.39	4.96	4.05	4.19	4.39	4.96	ns	
LVCMOS18, QUIETIO, 8 mA	1.18	1.30	1.43	2.04	3.71	3.85	4.05	4.63	3.71	3.85	4.05	4.63	ns	
LVCMOS18, QUIETIO, 12 mA	1.18	1.30	1.43	2.04	3.35	3.49	3.69	4.27	3.35	3.49	3.69	4.27	ns	
LVCMOS18, QUIETIO, 16 mA	1.18	1.30	1.43	2.04	3.20	3.34	3.54	4.14	3.20	3.34	3.54	4.14	ns	
LVCMOS18, QUIETIO, 24 mA	1.18	1.30	1.43	2.04	2.96	3.10	3.30	3.98	2.96	3.10	3.30	3.98	ns	
LVCMOS18, Slow, 2 mA	1.18	1.30	1.43	2.04	4.62	4.76	4.96	5.54	4.62	4.76	4.96	5.54	ns	
LVCMOS18, Slow, 4 mA	1.18	1.30	1.43	2.04	3.69	3.83	4.03	4.60	3.69	3.83	4.03	4.60	ns	
LVCMOS18, Slow, 6 mA	1.18	1.30	1.43	2.04	3.00	3.14	3.34	3.94	3.00	3.14	3.34	3.94	ns	
LVCMOS18, Slow, 8 mA	1.18	1.30	1.43	2.04	2.19	2.33	2.53	3.17	2.19	2.33	2.53	3.17	ns	
LVCMOS18, Slow, 12 mA	1.18	1.30	1.43	2.04	1.99	2.13	2.33	2.95	1.99	2.13	2.33	2.95	ns	
LVCMOS18, Slow, 16 mA	1.18	1.30	1.43	2.04	1.99	2.13	2.33	2.95	1.99	2.13	2.33	2.95	ns	

Table 29: IOB Switching Characteristics for the Automotive XA Spartan-6 and the Spartan-6Q Devices<sup>(1)</sup> (Cont'd)

I/O Standard	T <sub>IOP1</sub>		T <sub>IOOP</sub>		T <sub>IOTP</sub>		Units	
	Speed Grade		Speed Grade		Speed Grade			
	-3	-2	-3	-2	-3	-2		
LVCMOS33, Slow, 6 mA	1.41	1.59	2.79	2.99	2.79	2.99	ns	
LVCMOS33, Slow, 8 mA	1.41	1.59	2.79	2.99	2.79	2.99	ns	
LVCMOS33, Slow, 12 mA	1.41	1.59	2.53	2.73	2.53	2.73	ns	
LVCMOS33, Slow, 16 mA	1.41	1.59	2.45	2.65	2.45	2.65	ns	
LVCMOS33, Slow, 24 mA	1.41	1.59	2.42	2.62	2.42	2.62	ns	
LVCMOS33, Fast, 2 mA	1.41	1.59	4.05	4.25	4.05	4.25	ns	
LVCMOS33, Fast, 4 mA	1.41	1.59	2.66	2.86	2.66	2.86	ns	
LVCMOS33, Fast, 6 mA	1.41	1.59	2.46	2.66	2.46	2.66	ns	
LVCMOS33, Fast, 8 mA	1.41	1.59	2.21	2.41	2.21	2.41	ns	
LVCMOS33, Fast, 12 mA	1.41	1.59	1.80	2.00	1.80	2.00	ns	
LVCMOS33, Fast, 16 mA	1.41	1.59	1.80	2.00	1.80	2.00	ns	
LVCMOS33, Fast, 24 mA	1.41	1.59	1.80	2.00	1.80	2.00	ns	
LVCMOS25, QUIETIO, 2 mA	0.89	1.07	5.00	5.20	5.00	5.20	ns	
LVCMOS25, QUIETIO, 4 mA	0.89	1.07	3.85	4.05	3.85	4.05	ns	
LVCMOS25, QUIETIO, 6 mA	0.89	1.07	3.60	3.80	3.60	3.80	ns	
LVCMOS25, QUIETIO, 8 mA	0.89	1.07	3.34	3.54	3.34	3.54	ns	
LVCMOS25, QUIETIO, 12 mA	0.89	1.07	2.98	3.18	2.98	3.18	ns	
LVCMOS25, QUIETIO, 16 mA	0.89	1.07	2.79	2.99	2.79	2.99	ns	
LVCMOS25, QUIETIO, 24 mA	0.89	1.07	2.64	2.84	2.64	2.84	ns	
LVCMOS25, Slow, 2 mA	0.89	1.07	3.96	4.16	3.96	4.16	ns	
LVCMOS25, Slow, 4 mA	0.89	1.07	2.96	3.16	2.96	3.16	ns	
LVCMOS25, Slow, 6 mA	0.89	1.07	2.88	3.08	2.88	3.08	ns	
LVCMOS25, Slow, 8 mA	0.89	1.07	2.63	2.83	2.63	2.83	ns	
LVCMOS25, Slow, 12 mA	0.89	1.07	2.15	2.35	2.15	2.35	ns	
LVCMOS25, Slow, 16 mA	0.89	1.07	2.15	2.35	2.15	2.35	ns	
LVCMOS25, Slow, 24 mA	0.89	1.07	2.15	2.35	2.15	2.35	ns	
LVCMOS25, Fast, 2 mA	0.89	1.07	3.52	3.72	3.52	3.72	ns	
LVCMOS25, Fast, 4 mA	0.89	1.07	2.43	2.63	2.43	2.63	ns	
LVCMOS25, Fast, 6 mA	0.89	1.07	2.23	2.43	2.23	2.43	ns	
LVCMOS25, Fast, 8 mA	0.89	1.07	2.16	2.36	2.16	2.36	ns	
LVCMOS25, Fast, 12 mA	0.89	1.07	1.70	1.90	1.70	1.90	ns	
LVCMOS25, Fast, 16 mA	0.89	1.07	1.70	1.90	1.70	1.90	ns	
LVCMOS25, Fast, 24 mA	0.89	1.07	1.70	1.90	1.70	1.90	ns	
LVCMOS18, QUIETIO, 2 mA	1.25	1.43	6.11	6.31	6.11	6.31	ns	
LVCMOS18, QUIETIO, 4 mA	1.25	1.43	4.88	5.08	4.88	5.08	ns	
LVCMOS18, QUIETIO, 6 mA	1.25	1.43	4.20	4.40	4.20	4.40	ns	
LVCMOS18, QUIETIO, 8 mA	1.25	1.43	3.86	4.06	3.86	4.06	ns	
LVCMOS18, QUIETIO, 12 mA	1.25	1.43	3.49	3.69	3.49	3.69	ns	

Table 29: IOB Switching Characteristics for the Automotive XA Spartan-6 and the Spartan-6Q Devices<sup>(1)</sup> (Cont'd)

I/O Standard	$T_{IOPI}$		$T_{IOOP}$		$T_{IOTP}$		Units	
	Speed Grade		Speed Grade		Speed Grade			
	-3	-2	-3	-2	-3	-2		
LVCMOS12, QUIETIO, 6 mA	0.98	1.16	4.79	4.99	4.79	4.99	ns	
LVCMOS12, QUIETIO, 8 mA	0.98	1.16	4.43	4.63	4.43	4.63	ns	
LVCMOS12, QUIETIO, 12 mA	0.98	1.16	4.18	4.38	4.18	4.38	ns	
LVCMOS12, Slow, 2 mA	0.98	1.16	5.12	5.32	5.12	5.32	ns	
LVCMOS12, Slow, 4 mA	0.98	1.16	3.00	3.20	3.00	3.20	ns	
LVCMOS12, Slow, 6 mA	0.98	1.16	2.91	3.11	2.91	3.11	ns	
LVCMOS12, Slow, 8 mA	0.98	1.16	2.51	2.71	2.51	2.71	ns	
LVCMOS12, Slow, 12 mA	0.98	1.16	2.25	2.45	2.25	2.45	ns	
LVCMOS12, Fast, 2 mA	0.98	1.16	3.60	3.80	3.60	3.80	ns	
LVCMOS12, Fast, 4 mA	0.98	1.16	2.49	2.69	2.49	2.69	ns	
LVCMOS12, Fast, 6 mA	0.98	1.16	1.94	2.14	1.94	2.14	ns	
LVCMOS12, Fast, 8 mA	0.98	1.16	1.82	2.02	1.82	2.02	ns	
LVCMOS12, Fast, 12 mA	0.98	1.16	1.80	2.00	1.80	2.00	ns	
LVCMOS12_JEDEC, QUIETIO, 2 mA	1.57	1.75	6.53	6.73	6.53	6.73	ns	
LVCMOS12_JEDEC, QUIETIO, 4 mA	1.57	1.75	5.12	5.32	5.12	5.32	ns	
LVCMOS12_JEDEC, QUIETIO, 6 mA	1.57	1.75	4.81	5.01	4.81	5.01	ns	
LVCMOS12_JEDEC, QUIETIO, 8 mA	1.57	1.75	4.44	4.64	4.44	4.64	ns	
LVCMOS12_JEDEC, QUIETIO, 12 mA	1.57	1.75	4.20	4.40	4.20	4.40	ns	
LVCMOS12_JEDEC, Slow, 2 mA	1.57	1.75	5.14	5.34	5.14	5.34	ns	
LVCMOS12_JEDEC, Slow, 4 mA	1.57	1.75	2.99	3.19	2.99	3.19	ns	
LVCMOS12_JEDEC, Slow, 6 mA	1.57	1.75	2.90	3.10	2.90	3.10	ns	
LVCMOS12_JEDEC, Slow, 8 mA	1.57	1.75	2.50	2.70	2.50	2.70	ns	
LVCMOS12_JEDEC, Slow, 12 mA	1.57	1.75	2.26	2.46	2.26	2.46	ns	
LVCMOS12_JEDEC, Fast, 2 mA	1.57	1.75	3.60	3.80	3.60	3.80	ns	
LVCMOS12_JEDEC, Fast, 4 mA	1.57	1.75	2.49	2.69	2.49	2.69	ns	
LVCMOS12_JEDEC, Fast, 6 mA	1.57	1.75	1.94	2.14	1.94	2.14	ns	
LVCMOS12_JEDEC, Fast, 8 mA	1.57	1.75	1.83	2.03	1.83	2.03	ns	
LVCMOS12_JEDEC, Fast, 12 mA	1.57	1.75	1.80	2.00	1.80	2.00	ns	

**Notes:**

- The Spartan-6Q FPGA -1L values are listed in Table 28.

Table 30 summarizes the value of  $T_{IOTPHZ}$ .  $T_{IOTPHZ}$  is described as the delay from the T pin to the IOB pad through the output buffer of an IOB pad, when 3-state is enabled (i.e., a high impedance state). These delays are measured using LVCMOS25, Fast, 12 mA.

Table 30: IOB 3-state ON Output Switching Characteristics ( $T_{IOTPHZ}$ )

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
$T_{IOTPHZ}$	T input to Pad high-impedance	1.39	1.59	1.59	1.91	ns

Table 32: Output Delay Measurement Methodology (Cont'd)

Description	I/O Standard Attribute	R <sub>REF</sub> (Ω)	C <sub>REF</sub> <sup>(1)</sup> (pF)	V <sub>MEAS</sub> (V)	V <sub>REF</sub> (V)
SSTL, Class II, 2.5V	SSTL2_II	25	0	V <sub>REF</sub>	1.25
SSTL, Class II, 1.5V	SSTL15_II	25	0	V <sub>REF</sub>	0.75
LVDS (Low-Voltage Differential Signaling), 2.5V & 3.3V	LVDS_25, LVDS_33	100	0	0 <sup>(3)</sup>	—
BLVDS (Bus LVDS), 2.5V	BLVDS_25	Note 4	0	0 <sup>(3)</sup>	—
Mini-LVDS, 2.5V & 3.3V	MINI_LVDS_25, MINI_LVDS_33	100	0	0 <sup>(3)</sup>	—
RSDS (Reduced Swing Differential Signaling), 2.5V & 3.3V	RSDS_25, RSDS_33	100	0	0 <sup>(3)</sup>	—
TMDS (Transition Minimized Differential Signaling), 3.3V	TMDS_33	Note 5	0	0 <sup>(3)</sup>	—
PPDS (Point-to-Point Differential Signaling, 2.5V & 3.3V	PPDS_25, PPDS_33	100	0	0 <sup>(3)</sup>	—

**Notes:**

1. C<sub>REF</sub> is the capacitance of the probe, nominally 0 pF.
2. Per PCI specifications.
3. The value given is the differential output voltage.
4. See the *BLVDS Output Termination* section in [UG381, Spartan-6 FPGA SelectIO Resources User Guide](#).
5. See the *TMDS\_33 Termination* section in [UG381, Spartan-6 FPGA SelectIO Resources User Guide](#).

## Simultaneously Switching Outputs

Due to package electrical parasitics, a given package supports a limited number of simultaneous switching outputs (SSOs) when using fast, high-drive outputs. [Table 33](#) and [Table 34](#) provide guidelines for the recommended maximum allowable number of SSOs. These guidelines describe the maximum number of user I/O pins of an output signal standard that should simultaneously switch in the same direction, while maintaining a safe level of switching noise for that particular signal standard. Meeting these guidelines for the stated test conditions ensures that the FPGA operates free from the adverse effects of GND and power bounce.

For each device/package combination, [Table 33](#) provides the number of equivalent V<sub>CCO</sub>/GND pairs per bank. For each output signal standard and drive strength, [Table 34](#) recommends the maximum number of SSOs, switching in the same direction, allowed per V<sub>CCO</sub>/GND pair within an I/O bank. The guidelines are categorized by package style, slew rate, and output drive current. The number of SSOs are also specified by I/O bank. Multiply the appropriate numbers from each table to calculate the maximum number of SSOs allowed within an I/O bank. The guidelines assume that all pins within a bank use the same I/O standard. Exceeding these SSO guidelines can result in increased power or GND bounce, degraded signal integrity, or increased system jitter. For a given I/O standard, if the SSO limit per pair in [Table 34](#) is greater than the maximum I/O per pair in [Table 33](#), then there is no SSO limit for the exclusive use of that I/O standard.

The recommended maximum SSO values assume that the FPGA is soldered on a printed circuit board and that the board uses sound design practices. Due to the additional inductance introduced by the socket, the SSO values do not apply for FPGAs mounted in sockets. The SSO values assume that the V<sub>CCAUX</sub> is powered at 3.3V. Setting V<sub>CCAUX</sub> to 2.5V provides better SSO characteristics. For more detail, see [UG381: Spartan-6 FPGA SelectIO Resources User Guide](#).

Table 34: SSO Limit per V<sub>CCO</sub>/GND Pair (Cont'd)

V <sub>CCO</sub>	I/O Standard	Drive	Slew	SSO Limit per V <sub>CCO</sub> /GND Pair					
				All TQG144, CPG196, CSG225, FT(G)256, and LX devices in CSG324		All CS(G)484, FG(G)484, FG(G)676, FG(G)900, and LXT devices in CSG324			
				Bank 0/2	Bank 1/3	Bank 0/2	Bank 1/3/4/5		
2.5V	LVCMS25	2	Fast	38	43	38	43		
			Slow	46	52	46	48		
			QuietIO	57	64	57	59		
		4	Fast	21	24	21	23		
			Slow	26	31	26	27		
			QuietIO	33	32	33	30		
		6	Fast	15	17	15	16		
			Slow	19	22	19	19		
			QuietIO	25	23	25	19		
		8	Fast	12	15	12	14		
			Slow	15	18	15	16		
			QuietIO	21	19	21	16		
		12	Fast	1	3	1	1		
			Slow	2	7	2	4		
			QuietIO	3	8	3	8		
		16	Fast	1	3	1	1		
			Slow	3	7	3	3		
			QuietIO	4	9	4	8		
		24	Fast	N/A	3	N/A	1		
			Slow	N/A	5	N/A	2		
			QuietIO	N/A	8	N/A	6		
SSTL_2_I <sup>(3)</sup>				10	11	10	11		
SSTL_2_II <sup>(3)</sup>				N/A	7	N/A	7		
DIFF_SSTL_2_I <sup>(3)</sup>				30	33	30	33		
DIFF_SSTL_2_II <sup>(3)</sup>				N/A	21	N/A	24		

## Block RAM Switching Characteristics

Table 43: Block RAM Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
<b>Block RAM Clock to Out Delays</b>						
T <sub>RCKO_DO</sub>	Clock CLK to DOUT output (without output register) <sup>(1)</sup>	1.85	2.10	2.10	3.50	ns, Max
T <sub>RCKO_DO_REG</sub>	Clock CLK to DOUT output (with output register) <sup>(2)</sup>	1.60	1.75	1.75	2.30	ns, Max
<b>Setup and Hold Times Before/After Clock CLK</b>						
T <sub>RCKC_ADDR</sub> /T <sub>RCKC_ADDR</sub>	ADDR inputs for XC devices <sup>(3)</sup>	0.35/ 0.10	0.40/ 0.12	0.40/ 0.12	0.50/ 0.15	ns, Min
	ADDR inputs for XA and XQ devices <sup>(3)</sup>	0.35/ 0.17	N/A	0.40/ 0.17	0.50/ 0.15	ns, Min
T <sub>RDCK_DI</sub> /T <sub>RCKD_DI</sub>	DIN inputs <sup>(4)</sup>	0.30/ 0.10	0.30/ 0.10	0.30/ 0.10	0.40/ 0.15	ns, Min
T <sub>RCKC_EN</sub> /T <sub>RCKC_EN</sub>	Block RAM Enable (EN) input	0.22/ 0.05	0.25/ 0.06	0.25/ 0.06	0.44/ 0.10	ns, Min
T <sub>RCKC_REGCE</sub> /T <sub>RCKC_REGCE</sub>	CE input of output register	0.20/ 0.10	0.20/ 0.10	0.20/ 0.10	0.28/ 0.15	ns, Min
T <sub>RCKC_WE</sub> /T <sub>RCKC_WE</sub>	Write Enable (WE) input	0.25/ 0.10	0.33/ 0.10	0.33/ 0.10	0.28/ 0.15	ns, Min
<b>Maximum Frequency</b>						
F <sub>MAX</sub>	Block RAM in all modes	320	280	280	150	MHz

**Notes:**

1. T<sub>RCKO\_DO</sub> includes T<sub>RCKO\_DOA</sub> and T<sub>RCKO\_DOPA</sub> as well as the B port equivalent timing parameters.
2. T<sub>RCKO\_DO\_REG</sub> includes T<sub>RCKO\_DOA\_REG</sub> and T<sub>RCKO\_DOPA\_REG</sub> as well as the B port equivalent timing parameters.
3. The ADDR setup and hold must be met when EN is asserted (even when WE is deasserted). Otherwise, block RAM data corruption is possible.
4. T<sub>RDCK\_DI</sub> includes both A and B inputs as well as the parity inputs of A and B.

Table 45: Device DNA Interface Port Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
T <sub>DNASSU</sub>	Setup time on SHIFT before the rising edge of CLK		7			ns, Min
T <sub>DNASH</sub>	Hold time on SHIFT after the rising edge of CLK		1			ns, Min
T <sub>DNADSU</sub>	Setup time on DIN before the rising edge of CLK		7			ns, Min
T <sub>DNADH</sub>	Hold time on DIN after the rising edge of CLK		1			ns, Min
T <sub>DNARSU</sub>	Setup time on READ before the rising edge of CLK		7			ns, Min
			1,000			ns, Max
T <sub>DNARH</sub>	Hold time on READ after the rising edge of CLK		1			ns, Min
T <sub>DNADCKO</sub>	Clock-to-output delay on DOUT after rising edge of CLK		0.5			ns, Min
			6			ns, Max
T <sub>DNACLKF</sub> <sup>(2)</sup>	CLK frequency		2			MHz, Max
T <sub>DNACLKL</sub>	CLK Low time		50			ns, Min
T <sub>DNACLKH</sub>	CLK High time		50			ns, Min

**Notes:**

1. The minimum READ pulse width is 8 ns, the maximum READ pulse width is 1  $\mu$ s.
2. Also applies to TCK when reading DNA through the boundary-scan port.

Table 46: Suspend Mode Switching Characteristics

Symbol	Description	Min	Max	Units
<b>Entering Suspend Mode</b>				
T <sub>SUSPENDHIGH_AWAKE</sub>	Rising edge of SUSPEND pin to falling edge of AWAKE pin without glitch filter	2.5	14	ns
T <sub>SUSPENDFILTER</sub>	Adjustment to SUSPEND pin rising edge parameters when glitch filter enabled	31	430	ns
T <sub>SUSPEND_GWE</sub>	Rising edge of SUSPEND pin until FPGA output pins drive their defined SUSPEND constraint behavior (without glitch filter)	–	15	ns
T <sub>SUSPEND_GTS</sub>	Rising edge of SUSPEND pin to write-protect lock on all writable clocked elements (without glitch filter)	–	15	ns
T <sub>SUSPEND_DISABLE</sub>	Rising edge of the SUSPEND pin to FPGA input pins and interconnect disabled (without glitch filter)	–	1500	ns
<b>Exiting Suspend Mode</b>				
T <sub>SUSPENDLOW_AWAKE</sub>	Falling edge of the SUSPEND pin to rising edge of the AWAKE pin. Does not include DCM or PLL lock time.	7	75	$\mu$ s
T <sub>SUSPEND_ENABLE</sub>	Falling edge of the SUSPEND pin to FPGA input pins and interconnect re-enabled	7	41	$\mu$ s
T <sub>AWAKE_GWE1</sub>	Rising edge of the AWAKE pin until write-protect lock released on all writable clocked elements, using <b>sw_clk:InternalClock</b> and <b>sw_gwe_cycle:1</b> .	–	80	ns
T <sub>AWAKE_GWE512</sub>	Rising edge of the AWAKE pin until write-protect lock released on all writable clocked elements, using <b>sw_clk:InternalClock</b> and <b>sw_gwe_cycle:512</b> .	–	20.5	$\mu$ s
T <sub>AWAKE_GTS1</sub>	Rising edge of the AWAKE pin until outputs return to the behavior described in the FPGA application, using <b>sw_clk:InternalClock</b> and <b>sw_gts_cycle:1</b> .	–	80	ns
T <sub>AWAKE_GTS512</sub>	Rising edge of the AWAKE pin until outputs return to the behavior described in the FPGA application, using <b>sw_clk:InternalClock</b> and <b>sw_gts_cycle:512</b> .	–	20.5	$\mu$ s
T <sub>SCP_AWAKE</sub>	Rising edge of SCP pins to rising edge of AWAKE pin	7	75	$\mu$ s

Table 57: Switching Characteristics for the Digital Frequency Synthesizer DFS (DCM\_CLKGEN)<sup>(1)</sup>

Symbol	Description	Speed Grade								Units	
		-3		-3N		-2		-1L			
		Min	Max	Min	Max	Min	Max	Min	Max		
<b>Output Frequency Ranges (DCM_CLKGEN)</b>											
CLKOUT_FREQ_FX	Frequency for the CLKFX and CLKFX180 outputs	5	375	5	375	5	333	5	200	MHz	
CLKOUT_FREQ_FXDV	Frequency for the CLKFXDV output	0.15625	187.5	0.15625	187.5	0.15625	166.5	0.15625	100	MHz	
<b>Output Clock Jitter<sup>(2)(3)</sup></b>											
CLKOUT_PER_JITT_FX	Period jitter at the CLKFX and CLKFX180 outputs.	Typical = ±[0.2% of CLKFX period + 100]								ps	
CLKOUT_PER_JITT_FXDV	Period jitter at the CLKFXDV output.	Typical = ±[0.2% of CLKFX period + 100]								ps	
CLKFX_FREEZE_VAR	CLKFX period change in free running oscillator mode at the same temperature. FCLKFX > 50 MHz	Maximum = ±3% of CLKFX period								ps	
	CLKFX period change in free running oscillator mode at the same temperature. FCLKFX < 50 MHz	Maximum = ±5% of CLKFX period								ps	
CLKFX_FREEZE_TEMP_SLOPE	CLKFX period will change in free oscillator mode over temperature. Add to CLKFX_FREEZE_VAR to determine total CLKFX period change. Percentage change for CLKFX period over 1°C.	Maximum = 0.1								%/°C	
<b>Duty Cycle<sup>(4)(5)</sup></b>											
CLKOUT_DUTY_CYCLE_FX	Duty cycle precision for the CLKFX and CLKFX180 outputs, including the BUFGMUX and clock tree duty-cycle distortion	Maximum = ±[1% of CLKFX period + 350]								ps	
CLKOUT_DUTY_CYCLE_FXDV	Duty cycle precision for the CLKFXDV outputs, including the BUFGMUX and clock tree duty-cycle distortion	Maximum = ±[1% of CLKFX period + 350]								ps	
<b>Lock Time</b>											
LOCK_FX <sup>(2)</sup>	The time from deassertion at the DCM's Reset input to the rising transition at its LOCKED output. The DFS asserts LOCKED when the CLKFX, CLKFX180, and CLKFXDV signals are valid. Lock time requires CLKFX_DIVIDE < $F_{IN}/(0.50 \text{ MHz})$ when: $F_{CLKIN} < 50 \text{ MHz}$	–	50	–	50	–	50	–	50	ms	
	when: $F_{CLKIN} > 50 \text{ MHz}$	–	5	–	5	–	5	–	5	ms	

Table 59: Switching Characteristics for the Phase-Shift Clock in Variable Phase Mode<sup>(1)</sup>

Symbol	Description	Amount of Phase Shift	Units
<b>Phase Shifting Range</b>			
MAX_STEPS <sup>(2)</sup>	When CLKIN < 60 MHz, the maximum allowed number of DCM_DELAY_STEP steps for a given CLKIN clock period, where T = CLKIN clock period in ns. When using CLKIN_DIVIDE_BY_2 = TRUE, double the clock-effective clock period.	$\pm(\text{INTEGER}(10 \times (\text{CLKIN} - 3 \text{ ns})))$	steps
	When CLKIN $\geq$ 60 MHz, the maximum allowed number of DCM_DELAY_STEP steps for a given CLKIN clock period, where T = CLKIN clock period in ns. When using CLKIN_DIVIDE_BY_2 = TRUE, double the clock-effective clock period.	$\pm(\text{INTEGER}(15 \times (\text{CLKIN} - 3 \text{ ns})))$	steps
FINE_SHIFT_RANGE_MIN	Minimum guaranteed delay for variable phase shifting.	$\pm(\text{MAX_STEPS} \times \text{DCM_DELAY_STEP_MIN})$	ps
FINE_SHIFT_RANGE_MAX	Maximum guaranteed delay for variable phase shifting	$\pm(\text{MAX_STEPS} \times \text{DCM_DELAY_STEP_MAX})$	ps

**Notes:**

- The values in this table are based on the operating conditions described in Table 53 and Table 58.
- The maximum variable phase shift range, MAX\_STEPS, is only valid when the DCM has no initial fixed-phase shifting, that is, the PHASE\_SHIFT attribute is set to 0.
- The DCM\_DELAY\_STEP values are provided at the end of Table 54.

Table 60: Miscellaneous DCM Timing Parameters<sup>(1)</sup>

Symbol	Description	Min	Max	Units
DCM_RST_PW_MIN	Minimum duration of a RST pulse width	3	–	CLKIN cycles

**Notes:**

- This limit only applies to applications that use the DCM DLL outputs (CLK0, CLK90, CLK180, CLK270, CLK2X, CLK2X180, and CLKDV). The DCM DFS outputs (CLKFX, CLKFXDV, CLKFX180) are unaffected.

Table 61: Frequency Synthesis

Attribute	Min	Max
CLKFX_MULTIPLY (DCM_SP)	2	32
CLKFX_DIVIDE (DCM_SP)	1	32
CLKDV_DIVIDE (DCM_SP)	1.5	16
CLKFX_MULTIPLY (DCM_CLKGEN)	2	256
CLKFX_DIVIDE (DCM_CLKGEN)	1	256
CLKFXDV_DIVIDE (DCM_CLKGEN)	2	32

Table 62: DCM Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
T <sub>DMCCK_PSEN</sub> /T <sub>DMCKC_PSEN</sub>	PSEN Setup/Hold	1.50/ 0.00	1.50/ 0.00	1.50/ 0.00	1.50/ 0.00	ns
T <sub>DMCCK_PSINCDEC</sub> /T <sub>DMCKC_PSINCDEC</sub>	PSINCDEC Setup/Hold	1.50/ 0.00	1.50/ 0.00	1.50/ 0.00	1.50/ 0.00	ns
T <sub>DMCKO_PSDONE</sub>	Clock to out of PSDONE	1.50	1.50	1.50	1.50	ns

Table 64: Global Clock Input to Output Delay With DCM in System-Synchronous Mode

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
LVCMOS25 Global Clock Input to Output Delay using Output Flip-Flop, 12mA, Fast Slew Rate, <i>with</i> DCM in System-Synchronous Mode.							
TICKOFDCM	Global Clock and OUTFF <i>with</i> DCM	XC6SLX4	4.23	N/A	6.11	6.60	ns
		XC6SLX9	4.23	5.17	6.11	6.60	ns
		XC6SLX16	4.28	4.57	5.34	6.36	ns
		XC6SLX25	3.95	4.18	4.59	6.91	ns
		XC6SLX25T	3.95	4.18	4.59	N/A	ns
		XC6SLX45	4.37	4.70	5.50	6.85	ns
		XC6SLX45T	4.37	4.70	5.50	N/A	ns
		XC6SLX75	3.90	4.23	4.77	6.31	ns
		XC6SLX75T	3.90	4.23	4.77	N/A	ns
		XC6SLX100	3.86	4.16	4.66	7.25	ns
		XC6SLX100T	3.90	4.16	4.66	N/A	ns
		XC6SLX150	4.03	4.33	4.83	6.63	ns
		XC6SLX150T	4.03	4.33	4.83	N/A	ns
		XA6SLX4	4.55	N/A	6.11	N/A	ns
		XA6SLX9	4.55	N/A	6.11	N/A	ns
		XA6SLX16	4.62	N/A	5.33	N/A	ns
		XA6SLX25	4.27	N/A	4.59	N/A	ns
		XA6SLX25T	4.27	N/A	4.69	N/A	ns
		XA6SLX45	4.69	N/A	5.50	N/A	ns
		XA6SLX45T	4.69	N/A	5.50	N/A	ns
		XA6SLX75	4.22	N/A	4.77	N/A	ns
		XA6SLX75T	4.22	N/A	4.77	N/A	ns
		XA6SLX100	N/A	N/A	5.34	N/A	ns
		XQ6SLX75	N/A	N/A	4.77	6.31	ns
		XQ6SLX75T	4.22	N/A	4.77	N/A	ns
		XQ6SLX150	N/A	N/A	4.96	6.63	ns
		XQ6SLX150T	4.62	N/A	4.96	N/A	ns

**Notes:**

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. DCM output jitter is already included in the timing calculation.

Table 69: Global Clock Input to Output Delay With DCM and PLL in Source-Synchronous Mode

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
LVCMOS25 Global Clock Input to Output Delay using Output Flip-Flop, 12mA, Fast Slew Rate, <i>with</i> DCM in Source-Synchronous Mode and PLL in DCM2PLL Mode.							
TICKOFDCM0_PLL	Global Clock and OUTFF with DCM and PLL	XC6SLX4	5.58	N/A	7.42	8.54	ns
		XC6SLX9	5.58	6.19	7.42	8.54	ns
		XC6SLX16	5.50	6.06	7.05	8.24	ns
		XC6SLX25	5.57	6.04	7.02	8.33	ns
		XC6SLX25T	5.57	6.04	7.02	N/A	ns
		XC6SLX45	5.53	5.97	6.96	8.32	ns
		XC6SLX45T	5.53	5.97	6.96	N/A	ns
		XC6SLX75	5.55	6.00	6.99	8.54	ns
		XC6SLX75T	5.55	6.00	6.99	N/A	ns
		XC6SLX100	5.58	6.03	7.02	9.11	ns
		XC6SLX100T	5.62	6.03	7.02	N/A	ns
		XC6SLX150	5.32	5.70	6.41	8.26	ns
		XC6SLX150T	5.32	5.70	6.41	N/A	ns
		XA6SLX4	5.87	N/A	7.28	N/A	ns
		XA6SLX9	5.87	N/A	7.28	N/A	ns
		XA6SLX16	6.02	N/A	6.87	N/A	ns
		XA6SLX25	5.88	N/A	6.90	N/A	ns
		XA6SLX25T	5.88	N/A	7.00	N/A	ns
		XA6SLX45	5.82	N/A	6.81	N/A	ns
		XA6SLX45T	5.82	N/A	6.81	N/A	ns
		XA6SLX75	5.81	N/A	6.80	N/A	ns
		XA6SLX75T	5.81	N/A	6.80	N/A	ns
		XA6SLX100	N/A	N/A	6.88	N/A	ns
		XQ6SLX75	N/A	N/A	6.80	8.54	ns
		XQ6SLX75T	5.81	N/A	6.80	N/A	ns
		XQ6SLX150	N/A	N/A	6.41	8.26	ns
		XQ6SLX150T	5.90	N/A	6.41	N/A	ns

**Notes:**

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. DCM and PLL output jitter are already included in the timing calculation.

Table 71: Global Clock Setup and Hold Without DCM or PLL (Default Delay)

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
<b>Input Setup and Hold Time Relative to Global Clock Input Signal for LVCMOS25 Standard.<sup>(1)</sup></b>							
T <sub>PSFD</sub> / T <sub>PHFD</sub>	Default Delay <sup>(2)</sup> Global Clock and IFF <sup>(3)</sup> without DCM or PLL	XC6SLX4	0.66/1.17	N/A	1.05/0.79	2.09/1.05	ns
		XC6SLX9	0.66/1.17	0.75/1.17	1.05/1.17	2.09/1.05	ns
		XC6SLX16	0.87/1.16	0.93/1.16	0.96/1.16	1.86/1.06	ns
		XC6SLX25	0.68/0.77	0.81/0.81	0.87/0.82	2.21/1.33	ns
		XC6SLX25T	0.68/0.77	0.81/0.81	0.87/0.82	N/A	ns
		XC6SLX45	0.40/1.05	0.42/1.17	0.64/1.20	1.61/1.67	ns
		XC6SLX45T	0.40/1.05	0.42/1.17	0.64/1.20	N/A	ns
		XC6SLX75	0.41/1.11	0.41/1.13	0.80/1.14	1.23/1.82	ns
		XC6SLX75T	0.41/1.11	0.41/1.13	0.80/1.14	N/A	ns
		XC6SLX100	0.39/1.12	0.39/1.23	0.39/1.28	1.13/1.94	ns
		XC6SLX100T	0.39/1.12	0.39/1.23	0.39/1.28	N/A	ns
		XC6SLX150	0.23/1.54	0.23/1.62	0.23/1.62	1.14/2.05	ns
		XC6SLX150T	0.23/1.54	0.23/1.62	0.23/1.62	N/A	ns
		XA6SLX4	0.73/1.18	N/A	1.05/0.80	N/A	ns
		XA6SLX9	0.73/1.18	N/A	1.05/0.80	N/A	ns
		XA6SLX16	0.90/1.20	N/A	0.96/0.75	N/A	ns
		XA6SLX25	0.70/0.81	N/A	0.87/0.91	N/A	ns
		XA6SLX25T	0.76/0.81	N/A	1.03/0.91	N/A	ns
		XA6SLX45	0.40/1.06	N/A	0.64/1.20	N/A	ns
		XA6SLX45T	0.40/1.06	N/A	0.64/1.20	N/A	ns
		XA6SLX75	0.41/1.24	N/A	0.80/1.18	N/A	ns
		XA6SLX75T	0.41/1.24	N/A	0.80/1.18	N/A	ns
		XA6SLX100	N/A	N/A	0.86/1.55	N/A	ns
		XQ6SLX75	N/A	N/A	0.80/1.18	1.23/1.82	ns
		XQ6SLX75T	0.41/1.24	N/A	0.80/1.18	N/A	ns
		XQ6SLX150	N/A	N/A	0.28/1.57	1.14/2.05	ns
		XQ6SLX150T	0.28/1.78	N/A	0.28/1.57	N/A	ns

**Notes:**

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
2. Default delay uses IODELAY2 tap 0.
3. IFF = Input Flip-Flop or Latch.

Table 72: Global Clock Setup and Hold With DCM in System-Synchronous Mode

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
<b>Input Setup and Hold Time Relative to Global Clock Input Signal for LVCMOS25 Standard.<sup>(1)</sup></b>							
T <sub>PSDCM</sub> / T <sub>PHDCM</sub>	No Delay Global Clock and IFF <sup>(2)</sup> with DCM in System-Synchronous Mode	XC6SLX4	1.54/0.06	N/A	1.75/0.12	2.84/0.27	ns
		XC6SLX9	1.54/0.06	1.63/0.12	1.75/0.12	2.84/0.27	ns
		XC6SLX16	1.72/-0.18	1.87/-0.17	2.13/-0.17	2.31/0.26	ns
		XC6SLX25	1.70/-0.03	1.78/-0.02	2.00/-0.02	2.88/0.20	ns
		XC6SLX25T	1.70/0.07	1.78/0.08	2.00/0.08	N/A	ns
		XC6SLX45	1.74/-0.03	1.84/-0.02	2.02/-0.02	2.64/0.52	ns
		XC6SLX45T	1.74/-0.01	1.84/0.00	2.02/0.00	N/A	ns
		XC6SLX75	1.86/0.11	1.98/0.12	2.20/0.12	2.96/0.58	ns
		XC6SLX75T	1.86/0.11	1.98/0.12	2.20/0.12	N/A	ns
		XC6SLX100	1.64/0.07	1.72/0.08	1.97/0.08	2.70/0.99	ns
		XC6SLX100T	1.64/0.09	1.72/0.10	1.97/0.10	N/A	ns
		XC6SLX150	1.53/0.39	1.62/0.40	1.82/0.40	2.75/1.00	ns
		XC6SLX150T	1.53/0.39	1.62/0.40	1.82/0.40	N/A	ns
		XA6SLX4	1.65/0.16	N/A	1.75/0.26	N/A	ns
		XA6SLX9	1.65/0.16	N/A	1.75/0.26	N/A	ns
		XA6SLX16	1.88/0.02	N/A	2.13/0.03	N/A	ns
		XA6SLX25	1.80/0.16	N/A	2.05/0.17	N/A	ns
		XA6SLX25T	1.80/0.16	N/A	2.13/0.17	N/A	ns
		XA6SLX45	1.75/0.12	N/A	2.02/0.13	N/A	ns
		XA6SLX45T	1.75/0.12	N/A	2.02/0.13	N/A	ns
		XA6SLX75	1.87/0.11	N/A	2.20/0.12	N/A	ns
		XA6SLX75T	1.87/0.11	N/A	2.20/0.12	N/A	ns
		XA6SLX100	N/A	N/A	2.46/0.24	N/A	ns
		XQ6SLX75	N/A	N/A	2.20/0.12	2.96/0.58	ns
		XQ6SLX75T	1.87/0.11	N/A	2.20/0.12	N/A	ns
		XQ6SLX150	N/A	N/A	1.82/0.56	2.75/1.00	ns
		XQ6SLX150T	1.65/0.55	N/A	1.82/0.56	N/A	ns

**Notes:**

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage. These measurements include DCM CLK0 jitter.
2. IFF = Input Flip-Flop or Latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 73: Global Clock Setup and Hold With DCM in Source-Synchronous Mode

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
<b>Input Setup and Hold Time Relative to Global Clock Input Signal for LVCMOS25 Standard.<sup>(1)</sup></b>							
T <sub>PSDCM0</sub> / T <sub>PHDCM0</sub>	No Delay Global Clock and IFF <sup>(2)</sup> with DCM in Source-Synchronous Mode	XC6SLX4	0.71/0.65	N/A	0.72/1.22	1.58/1.18	ns
		XC6SLX9	0.71/0.69	0.71/1.19	0.72/1.36	1.58/1.18	ns
		XC6SLX16	0.86/0.52	0.92/0.57	1.04/0.60	1.02/1.06	ns
		XC6SLX25	0.84/0.58	0.90/0.59	1.01/0.59	1.58/1.07	ns
		XC6SLX25T	0.84/0.58	0.90/0.59	1.01/0.59	N/A	ns
		XC6SLX45	0.85/0.70	0.90/0.76	0.98/0.79	1.34/1.34	ns
		XC6SLX45T	0.85/0.70	0.90/0.76	0.98/0.79	N/A	ns
		XC6SLX75	1.00/0.62	1.06/0.63	1.15/0.63	1.65/1.46	ns
		XC6SLX75T	1.00/0.71	1.06/0.72	1.15/0.72	N/A	ns
		XC6SLX100	0.81/0.68	0.81/0.69	0.94/0.69	1.42/2.07	ns
		XC6SLX100T	0.81/0.68	0.81/0.69	0.94/0.69	N/A	ns
		XC6SLX150	0.68/0.98	0.69/0.99	0.79/0.99	1.45/1.60	ns
		XC6SLX150T	0.68/0.98	0.69/0.99	0.79/0.99	N/A	ns
		XA6SLX4	0.81/0.74	N/A	0.72/1.36	N/A	ns
		XA6SLX9	0.81/0.74	N/A	0.72/1.36	N/A	ns
		XA6SLX16	1.01/0.56	N/A	1.04/0.60	N/A	ns
		XA6SLX25	0.94/0.76	N/A	1.06/0.77	N/A	ns
		XA6SLX25T	0.94/0.76	N/A	1.14/0.77	N/A	ns
		XA6SLX45	0.86/0.74	N/A	0.98/0.78	N/A	ns
		XA6SLX45T	0.86/0.74	N/A	0.98/0.78	N/A	ns
		XA6SLX75	1.02/0.71	N/A	1.15/0.72	N/A	ns
		XA6SLX75T	1.02/0.71	N/A	1.15/0.72	N/A	ns
		XA6SLX100	N/A	N/A	1.37/0.75	N/A	ns
		XQ6SLX75	N/A	N/A	1.15/0.72	1.65/1.46	ns
		XQ6SLX75T	1.02/0.71	N/A	1.15/0.72	N/A	ns
		XQ6SLX150	N/A	N/A	0.79/1.15	1.45/1.60	ns
		XQ6SLX150T	0.73/1.15	N/A	0.79/1.15	N/A	ns

**Notes:**

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage. These measurements include DCM CLK0 jitter.
2. IFF = Input Flip-Flop or Latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 78: Duty Cycle Distortion and Clock-Tree Skew (Cont'd)

Symbol	Description	Device <sup>(1)</sup>	Speed Grade				Units
			-3	-3N	-2	-1L	
$T_{BUFIOSKEW}$	I/O clock tree skew across one clock region	LX4	0.06	N/A	0.06	0.07	ns
		LX9	0.06	0.06	0.06	0.07	ns
		LX16	0.06	0.06	0.06	0.07	ns
		LX25	0.06	0.06	0.06	0.07	ns
		LX25T	0.06	0.06	0.06	N/A	ns
		LX45	0.06	0.06	0.06	0.07	ns
		LX45T	0.06	0.06	0.06	N/A	ns
		LX75	0.06	0.06	0.06	0.07	ns
		LX75T	0.06	0.06	0.06	N/A	ns
		LX100	0.06	0.06	0.06	0.07	ns
		LX100T	0.06	0.06	0.06	N/A	ns
		LX150	0.06	0.06	0.06	0.07	ns
		LX150T	0.06	0.06	0.06	N/A	ns

**Notes:**

1. LXT devices are not available with a -1L speed grade. The LX4 is not available in -3N speed grade.
2. These parameters represent the worst-case duty cycle distortion observable at the pins of the device using LVDS output buffers. For cases where other I/O standards are used, IBIS can be used to calculate any additional duty cycle distortion that might be caused by asymmetrical rise/fall times.
3. The  $T_{CKSKEW}$  value represents the worst-case clock-tree skew observable between sequential I/O elements. Significantly less clock-tree skew exists for I/O registers that are close to each other and fed by the same or adjacent clock-tree branches. Use the Xilinx FPGA Editor and Timing Analyzer tools to evaluate clock skew specific to your application.
4. The  $T_{CKSKEW}$  is 0.43 ns for the XA6SLX100 device using a -2 speed grade and 0.22 ns for the XC6SLX100 devices using the -2 speed grade.

Table 79: Package Skew

Symbol	Description	Device	Package <sup>(2)</sup>	Value	Units
$T_{PKGSKEW}$	Package Skew <sup>(1)</sup>	LX4	TQG144	N/A	ps
			CPG196	23	ps
			CSG225	58	ps
		LX9	TQG144	N/A	ps
			CPG196	23	ps
			CSG225	58	ps
			FT(G)256	88	ps
			CSG324	64	ps
		LX16	CPG196	19	ps
			CSG225	70	ps
			FT(G)256	71	ps
			CSG324	54	ps
		LX25	FT(G)256	90	ps
			CSG324	61	ps
			FG(G)484	84	ps
		LX25T	CSG324	48	ps
			FG(G)484	112	ps

Table 81: Source-Synchronous Pin-to-Pin Setup/Hold and Clock-to-Out Using BUFI02 (Cont'd)

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
<b>Pin-to-Pin Clock-to-Out Using BUFI02</b>							
TICKOFCs	OFF clock-to-out using BUFI02 clock	XC6SLX4	5.51	N/A	6.95	8.45	ns
		XC6SLX9	5.51	5.89	6.95	8.45	ns
		XC6SLX16	5.31	5.70	6.67	8.21	ns
		XC6SLX25	5.53	6.00	7.02	8.72	ns
		XC6SLX25T	5.53	6.00	7.02	N/A	ns
		XC6SLX45	5.76	6.18	7.22	8.77	ns
		XC6SLX45T	5.76	6.18	7.22	N/A	ns
		XC6SLX75	5.94	6.46	7.57	9.72	ns
		XC6SLX75T	5.94	6.46	7.57	N/A	ns
		XC6SLX100	6.09	6.53	7.60	9.66	ns
		XC6SLX100T	6.09	6.53	7.60	N/A	ns
		XC6SLX150	6.29	6.69	7.81	9.94	ns
		XC6SLX150T	6.29	6.69	7.81	N/A	ns
		XA6SLX4	5.83	N/A	6.95	N/A	ns
		XA6SLX9	5.83	N/A	6.95	N/A	ns
		XA6SLX16	5.65	N/A	6.68	N/A	ns
		XA6SLX25	5.85	N/A	7.03	N/A	ns
		XA6SLX25T	5.85	N/A	7.03	N/A	ns
		XA6SLX45	6.07	N/A	7.25	N/A	ns
		XA6SLX45T	6.07	N/A	7.25	N/A	ns
		XA6SLX75	6.26	N/A	7.57	N/A	ns
		XA6SLX75T	6.26	N/A	7.57	N/A	ns
		XA6SLX100	N/A	N/A	7.48	N/A	ns
		XQ6SLX75	N/A	N/A	7.57	9.72	ns
		XQ6SLX75T	6.26	N/A	7.57	N/A	ns
		XQ6SLX150	N/A	N/A	7.81	9.94	ns
		XQ6SLX150T	6.62	N/A	7.81	N/A	ns